

| | |
|-------------------------|--|
| 1. Record Nr. | UNINA9910877115103321 |
| Titolo | Surface and thin film analysis : a compendium of principles, instrumentation, and applicaitons // edited by Gernot Friedbacher and Henning Bubert |
| Pubbl/distr/stampa | Weinheim, Germany, : Wiley-VCH, 2011 |
| ISBN | 1-283-14094-2 9786613140944 3-527-63694-3 3-527-63692-7 |
| Edizione | [2nd, completely rev. and enl. ed.] |
| Descrizione fisica | 1 online resource (559 p.) |
| Altri autori (Persone) | FriedbacherGernot BubertH (Henning) |
| Disciplina | 530.4275 541.33 |
| Soggetti | Thin films - Surfaces - Analysis Electron spectroscopy Spectrum analysis |
| Lingua di pubblicazione | Inglese |
| Formato | Materiale a stampa |
| Livello bibliografico | Monografia |
| Note generali | Description based upon print version of record. |
| Nota di bibliografia | Includes bibliographical references and index. |
| Nota di contenuto | pt. 1. Electron detection -- pt. 2. Ion detection -- pt. 3. Photon detection -- pt. 4. Scanning probe microscopy. |
| Sommario/riassunto | Surveying and comparing all techniques relevant for practical applications in surface and thin film analysis, this second edition of a bestseller is a vital guide to this hot topic in nano- and surface technology. This new book has been revised and updated and is divided into four parts - electron, ion, and photon detection, as well as scanning probe microscopy. New chapters have been added to cover such techniques as SNOM, FIM, atom probe (AP),and sum frequency generation (SFG). Appendices with a summary and comparison of techniques and a list of equipment suppliers make this book a rapid ref |